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Zu-Han Gu
Leonard M. Hanssen
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Contents

vii *Conference Committee*

SESSION 1 **THEORY AND ANALYSIS I**

7065 05 **Reduced Rayleigh equations in the scattering of s-polarized light from and its transmission through a film with two one-dimensional rough surfaces** [7065-47]
T. A. Leskova, A. A. Maradudin, Univ. of California, Irvine (United States)

7065 06 **The design of random surfaces that produce nonstandard refraction of light** [7065-04]
T. A. Leskova, A. A. Maradudin, Univ. of California, Irvine (United States); I. Simonsen, Norwegian Univ. of Science and Technology (Norway)

SESSION 2 **INSTRUMENTS AND APPLICATIONS I**

7065 07 **Utilization of the Scheimpflug-principle in scatterometer design** [7065-05]
C. Hahlweg, H. Rothe, Helmut Schmidt Univ., Univ. of the Federal Armed Forces Hamburg (Germany)

7065 08 **Variable-angle directional emissometer for moderate-temperature emissivity measurements** [7065-06]
A. R. Ellis, Sandia National Labs. (United States); H. M. Graham, Lockheed Martin Aeronautics Co. (United States); M. B. Sinclair, J. C. Verley, Sandia National Labs. (United States)

7065 09 **Improved hyperspectral imagery using diffuse illumination or a polarizer** [7065-07]
D. Wellems, D. Bowers, Applied Technology Associates (United States)

SESSION 3 **THEORY AND ANALYSIS II**

7065 0B **Modeling scatter in composite media (Invited Paper)** [7065-09]
E. C. Fest, Raytheon Missile Systems (United States)

7065 0D **Goos-Haenchen effect applied for the design of Collett-Wolf beams** [7065-11]
Z.-H. Gu, Surface Optics Corp. (United States); A. Wang, Surface Optics Corp. (United States) and Univ. of Science and Technology of China (China)

7065 0E **Unification of geometric and diffractive scattering from random rough surfaces** [7065-12]
B. Aschenbach, Max-Planck-Institut für extraterrestrische Physik (Germany)

SESSION 4 INSTRUMENTS AND APPLICATIONS II

7065 0F **An infrared laser-based reflectometer for low reflectance measurements of samples and cavity structures** [7065-13]
J. Zeng, L. Hanssen, National Institute of Standards and Technology (United States)

7065 0G **Controlling and measuring the polarization state of light using compound gratings and other plasmonic/photonic crystal structures and applications to polarimetric sensors** [7065-14]
D. Crouse, City College of New York (United States)

7065 0H **Rough surface scatterometry of bodies with rotational symmetry** [7065-15]
C. Hahlweg, H. Rothe, Helmut Schmidt Univ., Univ. of the Federal Armed Forces Hamburg (Germany)

7065 0I **A fast and accurate image-based measuring system for isotropic reflection materials** [7065-16]
D. B. Kim, K. Y. Kim, K. S. Park, M. K. Seo, K. H. Lee, Gwangju Institute of Science and Technology (South Korea)

SESSION 5 OPTICAL DIAGNOSTICS I

7065 0L **Control of tiny dew droplet deposited on a copper plate by scattered laser light** [7065-19]
S. Matsumoto, Univ. of Industrial Technology (Japan)

7065 0M **An optical accessory for absolute reflection and transmission measurements in the wavelength region from 0.24μm to 25μm** [7065-20]
E. Kawate, National Institute of Advanced Industrial Science and Technology (Japan)

SESSION 6 TISSUE OPTICS AND DRUG ANALYSIS

7065 0O **Scattering depolarization by a bio-medium with anisotropic bio-molecules** [7065-22]
T.-W. Nee, S.-M. Foeng Nee, National Yang Ming Univ. (Taiwan)

7065 0P **Polarization of dipole scattering by isotropic medium** [7065-23]
S.-M. Foeng Nee, T.-W. Nee, National Yang Ming Univ. (Taiwan)

7065 0Q **Spatially resolved spectral imaging of pharmaceutical powders** [7065-24]
G. E. Carver, S. Rangwala, Princeton Lightwave (United States)

SESSION 7 OPTICAL DIAGNOSTICS II

7065 0R **Light-scattering properties of a woven shade-screen material used for daylighting and solar heat-gain control** [7065-25]
J. C. Jonsson, E. S. Lee, M. Rubin, Lawrence Berkeley National Lab. (United States)

7065 0T **Analysis of the uniqueness of an inverse grating characterization method** [7065-27]
B. Trauter, Carl Zeiss SMT (Germany) and Univ. of Heidelberg (Germany); J. Hetzler, Carl Zeiss SMT (Germany); K.-H. Brenner, Univ. of Heidelberg (Germany)

7065 0U **NIR reflectance method to determine moisture content in food products** [7065-28]
C. V. K. Kandala, USDA Agricultural Research Service (United States); G. Konda Naganathan, J. Subbiah, Univ. of Nebraska (United States)

SESSION 8 THEORY AND ANALYSIS III

7065 0V **Representative layer theory: describing absorption by particulate samples (Invited Paper)** [7065-29]
K. D. Dahm, D. J. Dahm, Rowan Univ. (United States)

7065 0W **A procedural model of reflection from random rough surfaces** [7065-30]
L. M. Hanssen, A. V. Prokhorov, National Institute of Standards and Technology (United States)

7065 0X **Modeling of femtosecond pulse propagation through dense scattering media** [7065-31]
N. Rivière, M. Barthélèmy, T. Dartigalongue, L. Hespel, Onera (France)

SESSION 9 OPTICAL DIAGNOSTICS III

7065 0Y **A comparison of optical properties between high density and low density sintered PTFE** [7065-33]
B. K. Tsai, D. W. Allen, L. M. Hanssen, B. Wilthan, J. Zeng, National Institute of Standards and Technology (United States)

7065 0Z **Pump probe experiment for high scattering media diagnostics** [7065-34]
M. Barthélemy, N. Rivière, L. Hespel, T. Dartigalongue, Onera (France)

POSTER SESSION

7065 12 **Steel hardness and their optical properties** [7065-37]
J. G. Suárez-Romero, Instituto Tecnológico de Querétaro (Mexico); E. Tepichin-Rodríguez, Instituto Nacional de Astrofísica Óptica y Electrónica (Mexico); E. Secundino-Palma, Instituto Tecnológico de Querétaro (Mexico); E. Hernandez-Gomez, Centro de Investigación en Ciencia Aplicada y Tecnologica Avanzada (Mexico)

7065 15 **Measurement method of optical scatter using a STAR GEM as a scatterometer** [7065-40]
E. Kawate, National Institute of Advanced Industrial Science and Technology (Japan) and TRAS Inc. (Japan)

7065 16 **Determining thickness of films on a curved substrate by use of ellipsometric measurement** [7065-41]
C.-Y.Han, National United Univ. (Taiwan); Z.-Y. Lee, Y.-F. Chao, National Chiao Tung Univ. (Taiwan)

7065 17 **Temperature fiber optic sensor using a thermosensible hydrogel** [7065-42]
R. Coello, M. Arcos, D. Chana, K. Contreras, G. Baldwin, J. C. Rueda, Pontificia Univ. Católica del Perú (Peru); M. Lomer, Univ. of Cantabria (Spain)

7065 18 **Optical diffraction by inhomogeneous volume objects** [7065-43]
G. Forte, A. Lencina, M. Tebaldi, N. Bolognini, Ctr. de Investigaciones Ópticas (Argentina) and Univ. Nacional de La Plata (Argentina)

7065 1A **Combining CPP-ACP with fluoride: a synergistic remineralization potential of artificially demineralized enamel or not?** [7065-45]
I. I. El-Sayad, Cairo Univ. (Egypt); A. K. Sakr, Misr Univ. of Science and Technology (Egypt); Y. A. Badr, National Laser Institute of Laser Enhanced Sciences, Cairo Univ. (Egypt)

Author Index

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1 Theory and Analysis I
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2 Instruments and Applications I
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3 Theory and Analysis II
David A. Cardimona, Air Force Research Laboratory (United States)

4 Instruments and Applications II
Soe-Mie F. Nee, National Yang-Ming University (Taiwan)

5 Optical Diagnostics I
Leonard M. Hanssen, National Institute of Standards and Technology (United States)

6 Tissue Optics and Drug Analysis
Gary E. Carver, Princeton Lightwave Corporation (United States)

7 Optical Diagnostics II
Michael E. Thomas, The Johns Hopkins University Applied Physics Laboratory (United States)

8 Theory and Analysis III
Zu-Han Gu, Surface Optics Corporation (United States)

9 Optical Diagnostics III
Mei Graham, Lockheed Martin Corporation (United States)